



# Non-magnetic metal thin film chip resistors

## ■ NRG series

### Features

- Thin film chip resistors using non-magnetic materials
- Long term stability with inorganic passivation
- High precision resistance tolerance:  $\pm 0.05\%$ , very small TCR:  $\pm 5\text{ppm}/^\circ\text{C}$
- Thin film structure enabling low noise and anti-sulfur

### Applications

- Medical electronics, industrial measurement instrumentation
- equipment/devices under magnetic field



## ◆ Part numbering system

**NRG 2012 V - 104 - W - T1**

Series code

Size: NRG1608, NRG2012, NRG3216

Temperature coefficient of resistance

Packaging quantity:  
T1(1,000pcs), T5(5,000pcs)

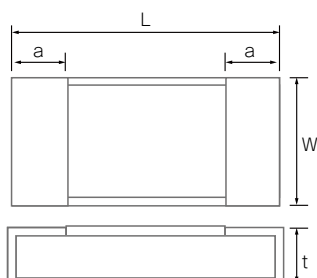
Resistance tolerance

Nominal resistance value  
(E-24: 3 digit, E-96: 4 digit, NRG6432: all 4 digit)

## ◆ Electrical Specification

Type	Power ratings	Temperature coefficient of resistance (ppm/ $^\circ\text{C}$ )	Resistance range( $\Omega$ ) Resistance tolerance			Maximum voltage	Resistance value series	Operating temperature	Packaging quantity
			$\pm 0.05\%$ (W)	$\pm 0.1\%$ (B)	$\pm 0.5\%$ (D)				
NRG1608	1/10W	$\pm 5$ (V)	100 $\leq R <$ 5.1k			100V			
		$\pm 10$ (N)	47 $\leq R \leq$ 270k						
		$\pm 25$ (P)	47 $\leq R \leq$ 270k	47 $\leq R \leq$ 332k	47 $\leq R \leq$ 360k				
		$\pm 50$ (Q)	—	—	10 $\leq R <$ 47				
NRG2012	1/8W	$\pm 5$ (V)	100 $\leq R <$ 10.2k			150V	E-24,E-96	-55 $^\circ\text{C}$ ~ 155 $^\circ\text{C}$	T1 T5
		$\pm 10$ (N)	47 $\leq R \leq$ 475k						
		$\pm 25$ (P)	47 $\leq R \leq$ 475k	47 $\leq R \leq$ 1M					
		$\pm 50$ (Q)	—	—	10 $\leq R <$ 47				
NRG3216	1/4W	$\pm 5$ (V)	100 $\leq R <$ 33.2k			200V			
		$\pm 10$ (N)	47 $\leq R \leq$ 1M						
		$\pm 25$ (P)	47 $\leq R \leq$ 1M						
		$\pm 50$ (Q)	—	—	10 $\leq R <$ 47				

## ◆ Dimensions



Type	Size (inch)	L	W	a	t
NRG1608	0603	1.60 $\pm$ 0.20	0.80+0.25/-0.20	0.30 $\pm$ 0.20	0.40+0.15/-0.10
NRG2012	0805	2.00 $\pm$ 0.20	1.25+0.25/-0.20	0.40 $\pm$ 0.20	0.40+0.15/-0.10
NRG3216	1206	3.20 $\pm$ 0.20	1.60 $\pm$ 0.25	0.50 $\pm$ 0.25	0.40+0.15/-0.10

(unit : mm)

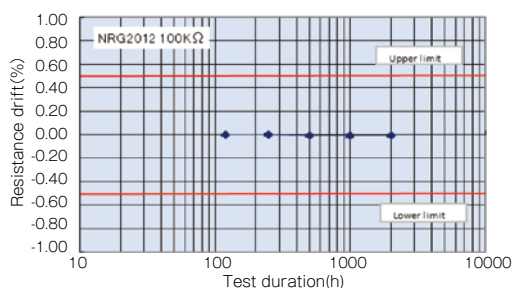
## ◆ Reliability specification

Test items	Condition (test methods (MIL-PRF-55342/JIS C5201-1))	Standard
Short time overload	2.5 x rated voltage, <sup>*1</sup> 5seconds	±0.5%
Life (biased)	70°C, rated voltage, <sup>*1</sup> 90min on 30min off, 2000hours	±0.5%
High temperature high humidity	85°C, 85%RH, 1/10 of rated power, 90min on 30min off, 2000hours	±0.5%
Temperature shock	-65°C (30min) ~ 150°C (30min) 100cycles	±0.5%
High temperature exposure	155°C, no bias, 1000hours	±0.5%
Resistance to soldering heat	260±5°C, 10 seconds (reflow)	±0.05%

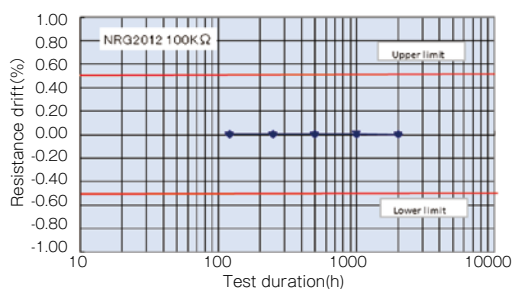
\*1 Rated voltage is given by  $E = \sqrt{R \times P}$  E= rated voltage (V), R=nominal resistance value(Ω), P=rated power(W)  
If rated voltage exceeds maximum voltage /element, maximum voltage/element is the rated voltage.

## ◆ Reliability test data

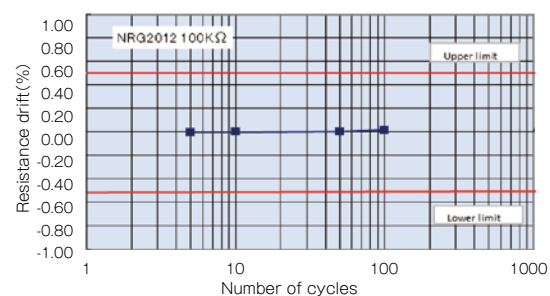
### ○ Biased life test



### ○ High temperature high humidity (biased)



### ○ Temperature shock



## ◆ Derating Curve

